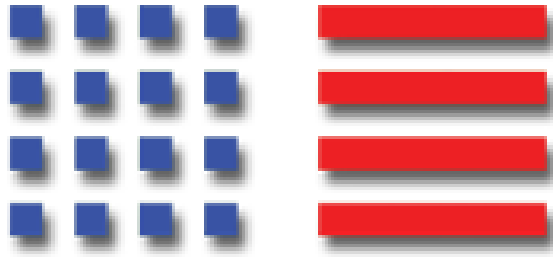


6th Belle II PXD/SVD workshop and 17th International Workshop on
DEPFET Detectors and Applications



Contribution ID: 50

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Summary of DEPFET characteristics measured on beam tests

Thursday, 2 October 2014 14:30 (20 minutes)

Presenter: SCHWENKER, Benjamin (Göttingen)

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